
Prediction of Interconnect Net-Degree Distribution Based on Rent's Rule

Tao Wan and Malgorzata Chrzanowska-
Jeske

Department of Electrical and Computer Engineering
Portland State University

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Outline

- Motivation
- Previous work
- Our models:
 - Model 1: Linear
 - Model 2: Exponential
 - Model 3: Weighted exponential
- Experimental results
- Behavior of internal fraction factor f
- Results
- Conclusions

A priori Interconnect Prediction

- Interconnect: importance of wires increases (they do not scale as devices do)
 - delay, power, area
- *A priori*:
 - before the actual layout is generated
 - very little information is known
- To narrow the solution search space
- To reduce the number of iterations
- To evaluate new architectures

Rent's Rule

Rent's rule: underlying assumption for most of the interconnect prediction techniques.

$$T = kB^p$$

T : number of terminals

B : number of blocks

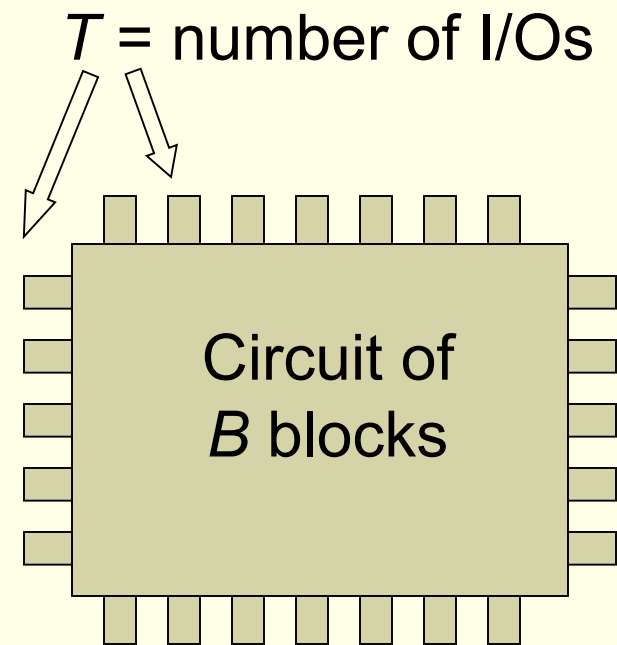
k : Rent coefficient

- average number of terminals per block

p : Rent exponent

- interconnect complexity

- level of placement optimization

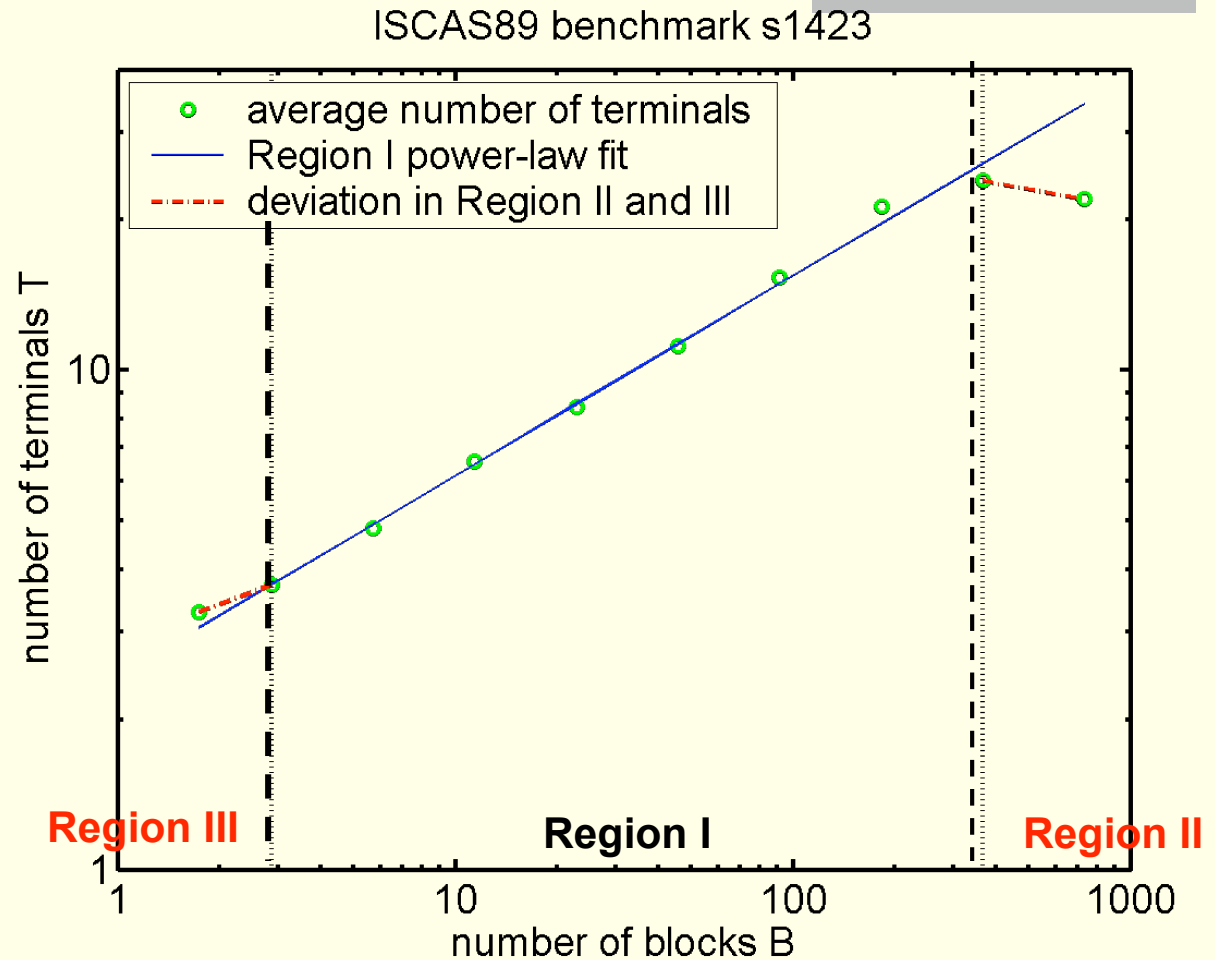


Rent's Rule

Region I: good approximation

Region II: high B
- technology constraints, limited pins
- psychological constraints, designers

Region III: low B
- mismatch between local and global interconnect complexity, FPGAs

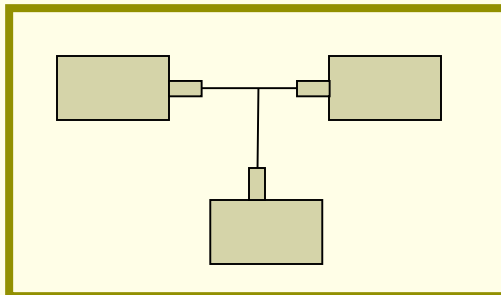


What is a Net-Degree Distribution?

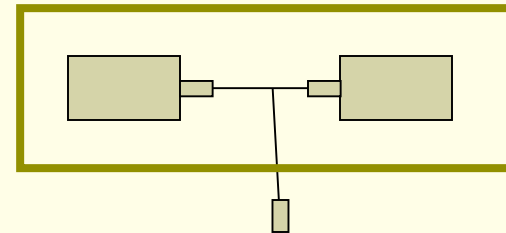
A net-degree distribution is a collection of values, indicating, for each net degree i , how many nets have a net degree equal i .

ISCAS89 s1423 net-degree distribution

net degree	1	2	3	4	5	6	7	8	9	10
number of nets	0	568	58	65	23	12	12	2	2	3



Internal 3-terminal net



External 3-terminal net

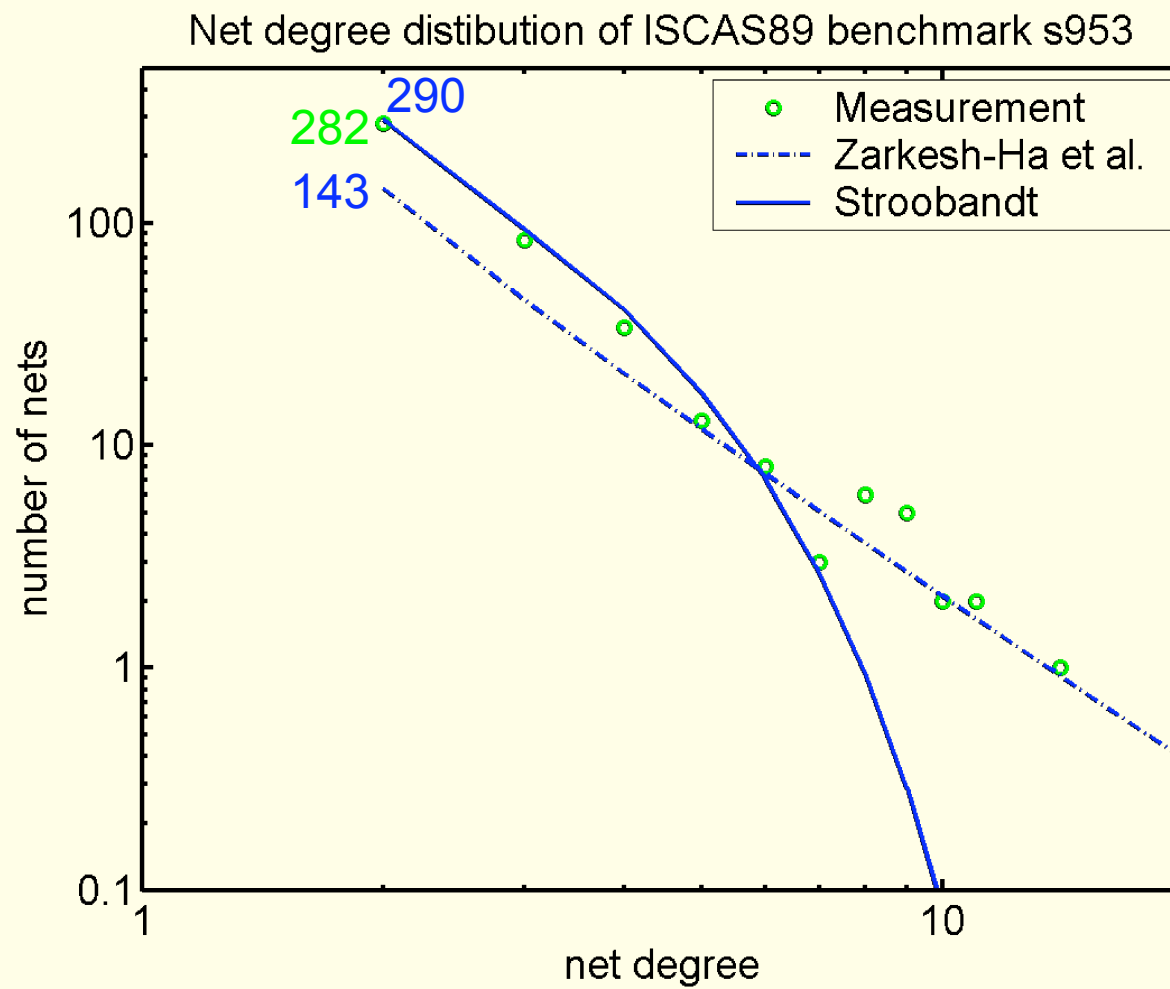
Why Net-Degree Distribution ?

- For a *priori* interconnect prediction, the most important parameter to predict is wire length
- Most current estimation techniques on wire length distribution are based on two-terminal nets
 - not accurate, lots of wires in current design are multi-terminal nets
 - multi-terminal nets do change conventional wire length distribution models

Why Net-Degree Distribution ?

- To evaluate total wire length - we have to accurately estimate the net-degree distribution
- Current net-degree distribution models not accurate
 - Zarkesh-Ha et al.'s model underestimates the number of nets with small net degrees
 - Stroobandt's model underestimates the number of nets with high net degrees
- The goal of this research was to derive more accurate net-degree distribution models

Previous Work



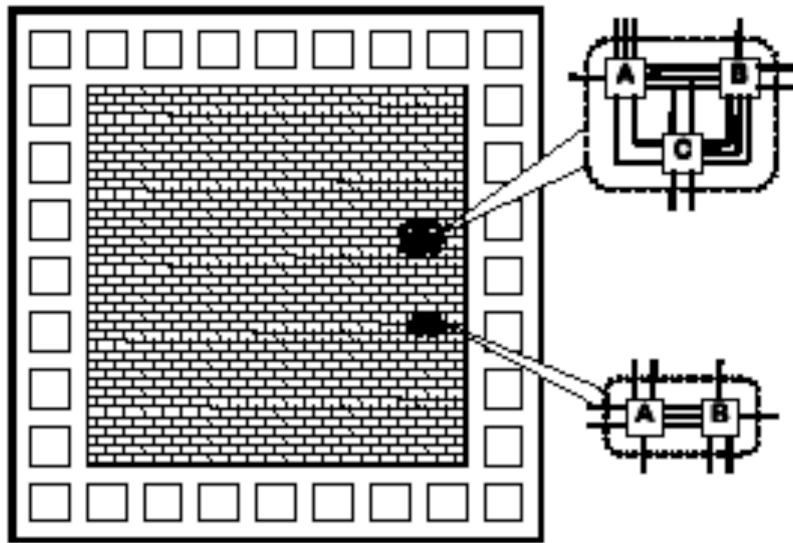
Zarkesh-Ha et al.'s Model

- A closed form expression for fan-out (net-degree) distribution
- Depends on Rent's parameters k , p and circuit size B only
- Underestimates the distribution for low net degrees, finds inaccurate total number of nets and average net degree

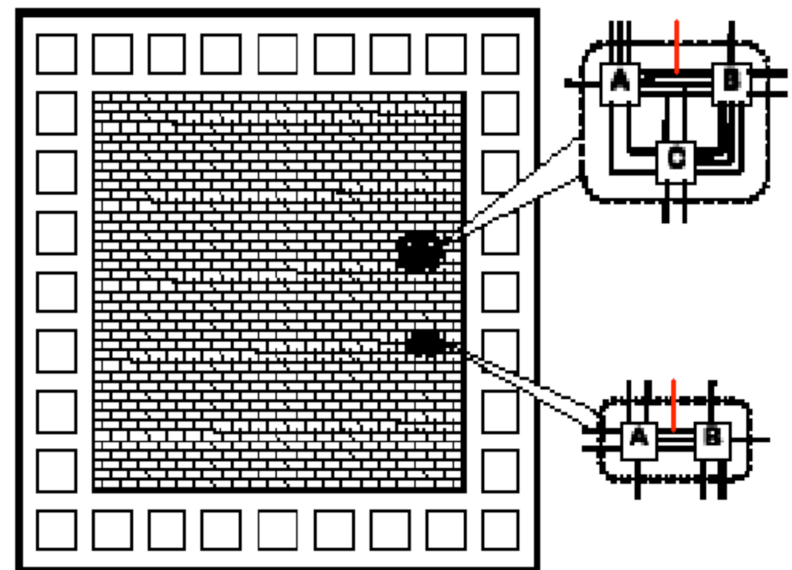
Zarkesh-Ha et al.'s Model

Zarkesh-Ha et al. made a few inaccurate assumptions

- Did not consider external nets



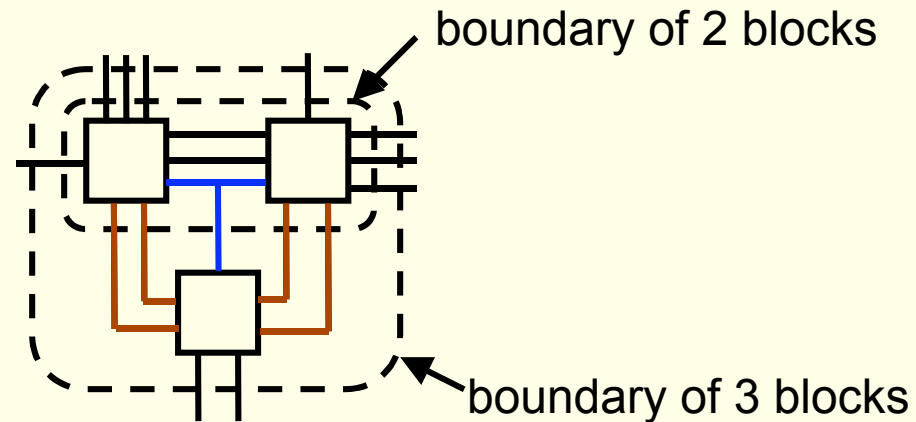
Their original circuit model



Their circuit model with external nets

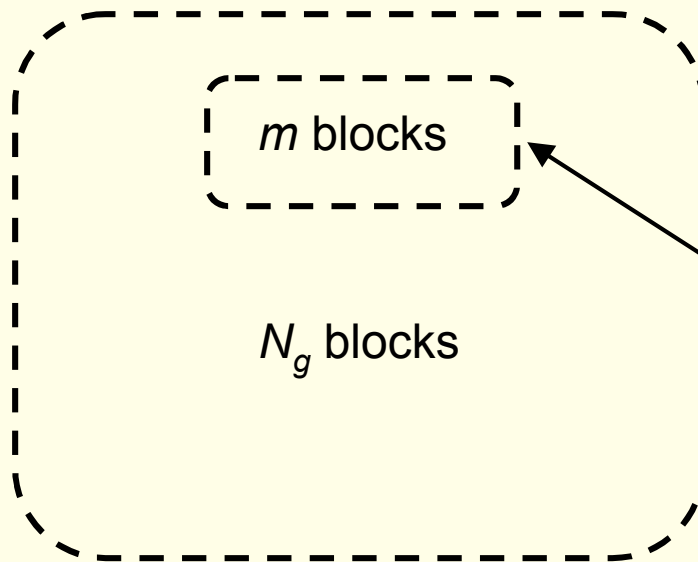
Zarkesh-Ha et al.'s Model

- They assumed that adding one block to the boundary of $m-1$ blocks would only introduce m -terminal nets, which is not valid in most circumstances
 - new nets don't have to be connected to all the blocks in the boundary



Zarkesh-Ha et al.'s Model

- They changed the definition of $T_{Net}(m)$, more specifically, they changed the boundary



They derived the expression of $T_{Net}(m)$ for the boundary of m blocks

$$T_{Net}(m) = k((m-1)^{p-1} - m^{p-1})$$

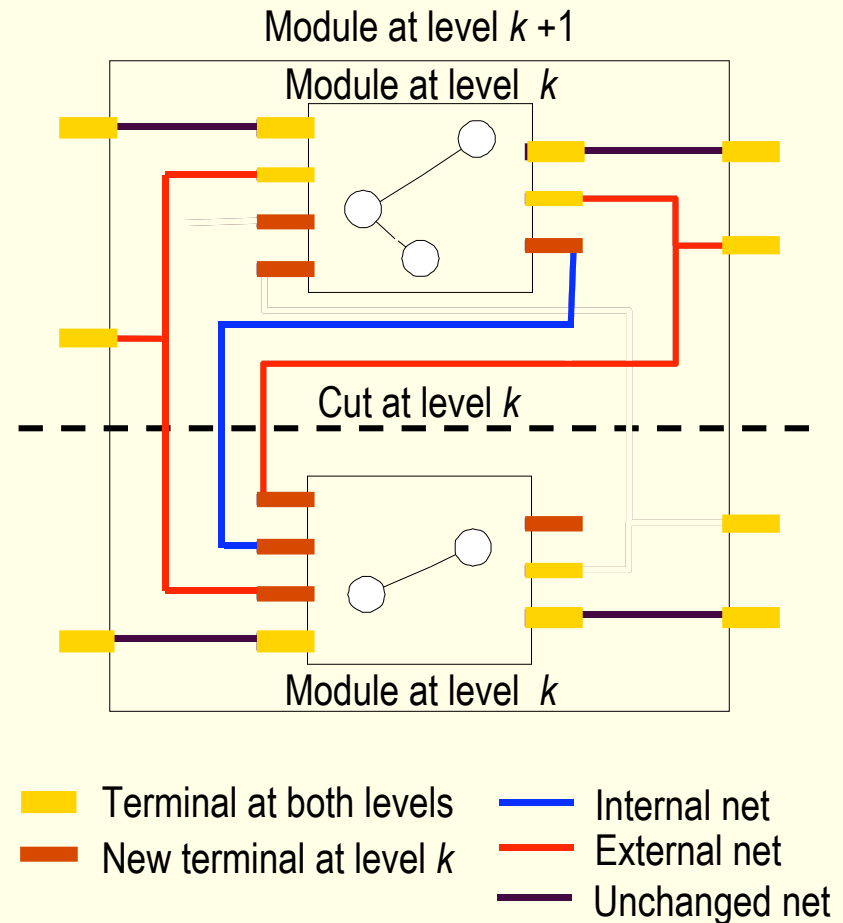
But when they applied it to the whole circuit consisting of N_g blocks, they forgot to substitute N_g for m

Stroobandt's Model

- Hierarchical model with recursive net-degree distribution
- Depends on Rent's parameters k , p , circuit size B , and several circuit parameters, such as internal fraction factor f or ratio of number of new input terminals to total number of new terminals α
- More accurate total number of nets and average net degree
- Underestimate the distribution for high net degrees
 - Maximum fan-out (maximum net degree - 1)

Stroobandt's Model

- Stroobandt's derivation is based on the relationship between the number of new terminals and the number of nets cut
- His derivation did not consider the effect of Region II of Rent's rule and did not take into account
 - technology constraint
 - psychological constraint



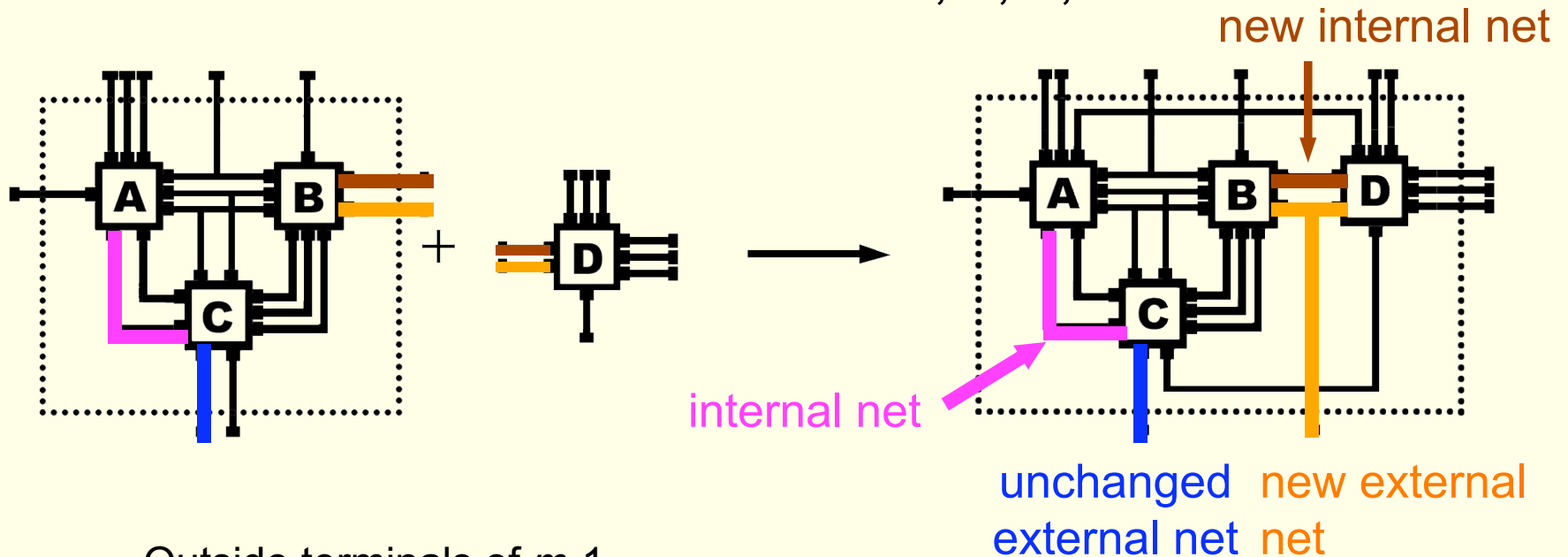
(Source: Stroobandt's paper)

Our Models

- Zarkesh-Ha et al. were interested in the number of terminals shared through an i -terminal net for each block. Stroobandt analyzed the number of new terminals generated by cutting nets.
- We directly look into the net-degree distribution
 - net-degree distribution $N(i)|_m$
 - internal net-degree distribution $N_i(i)|_m$
 - external net-degree distribution $N_e(i)|_m$
 - their normalized expressions $nN(i)|_m$, $nN_i(i)|_m$ and $nN_e(i)|_m$
- We record the change of $nN_i(i)|_m$ and $nN_e(i)|_m$ when circuit grows

Model 1: Linear

Grow from $m-1$ blocks to m blocks: 1, 2, 3, 4...



Outside terminals of $m-1$ blocks have equal probability to be selected for combining

internal fraction factor f

$$f = \frac{\text{new internal net}}{\text{new internal net} + \text{new external net}}$$

Model 1: Linear

Algorithm net-degree-distribution(M)

Input: M, f, p, k

Output: net-degree distribution N

begin

initialize vectors: nN_i , nN_e , and N ;

$nN_e(2)=k$; (* nN_e distribution for a single block*)

for $i=2$ to M **do**

 update nN_i and nN_e ;

end for

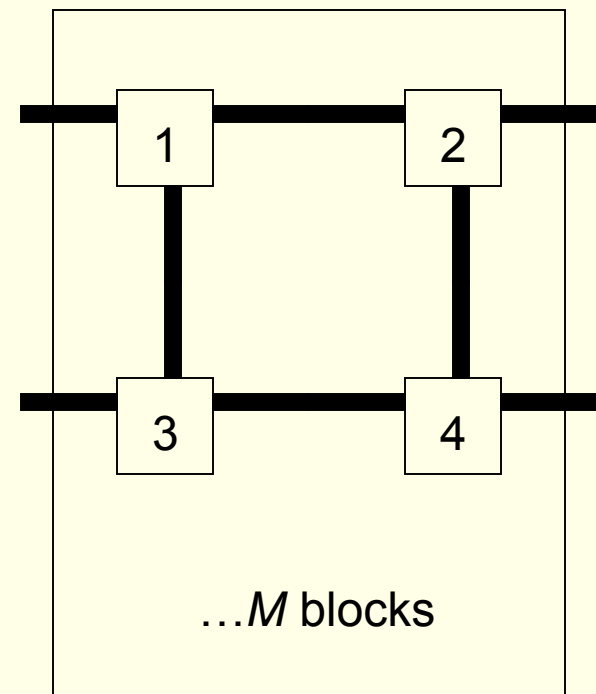
for $i=2$ to M **do**

$N(i)=\text{round}(nN_i(i)*M+nN_e(i)*M)$;

end for

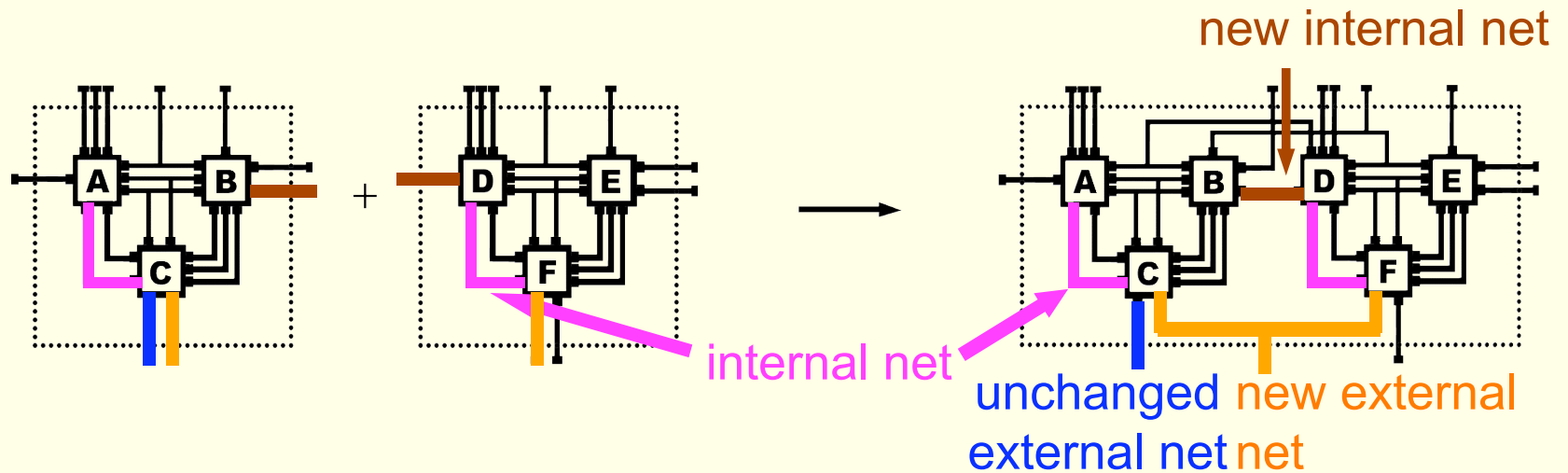
end.

A circuit of M blocks



Model 2: Exponential

Grow from m blocks to $2m$ blocks: 1, 2, 4, 8...



Outside terminals of m blocks have equal probability to be selected for combining

internal fraction factor f

$$f = \frac{\text{new internal net}}{\text{new internal} + \text{new external}}$$

Model 2: Exponential

Algorithm net-degree-distribution(M)

Input: M, f, p, k

Output: net-degree distribution N

begin

initialize vectors: nN_i , nN_e , and N ;

$nN_e(2)=k$; (* nN_e distribution for a single block*)

$N=\text{ceil}(\log_2 M)$; (*Determine the number of iterations*)

for $h=0$ to $N-1$ **do**

$m1=2^h$;

$m2=2^{h+1}$;

 update nN_i and nN_e ;

end for

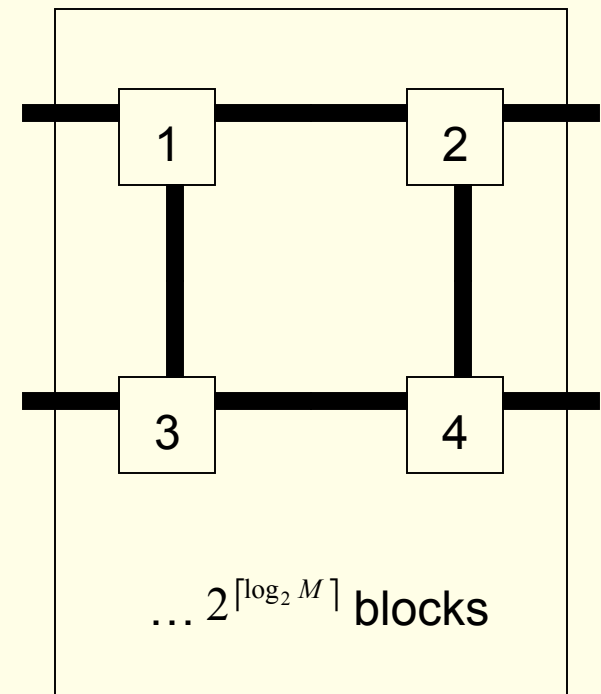
for $i=2$ to M **do**

$N(i)=\text{round}(nN_i(i)*M+nN_e(i)*M)$;

end for

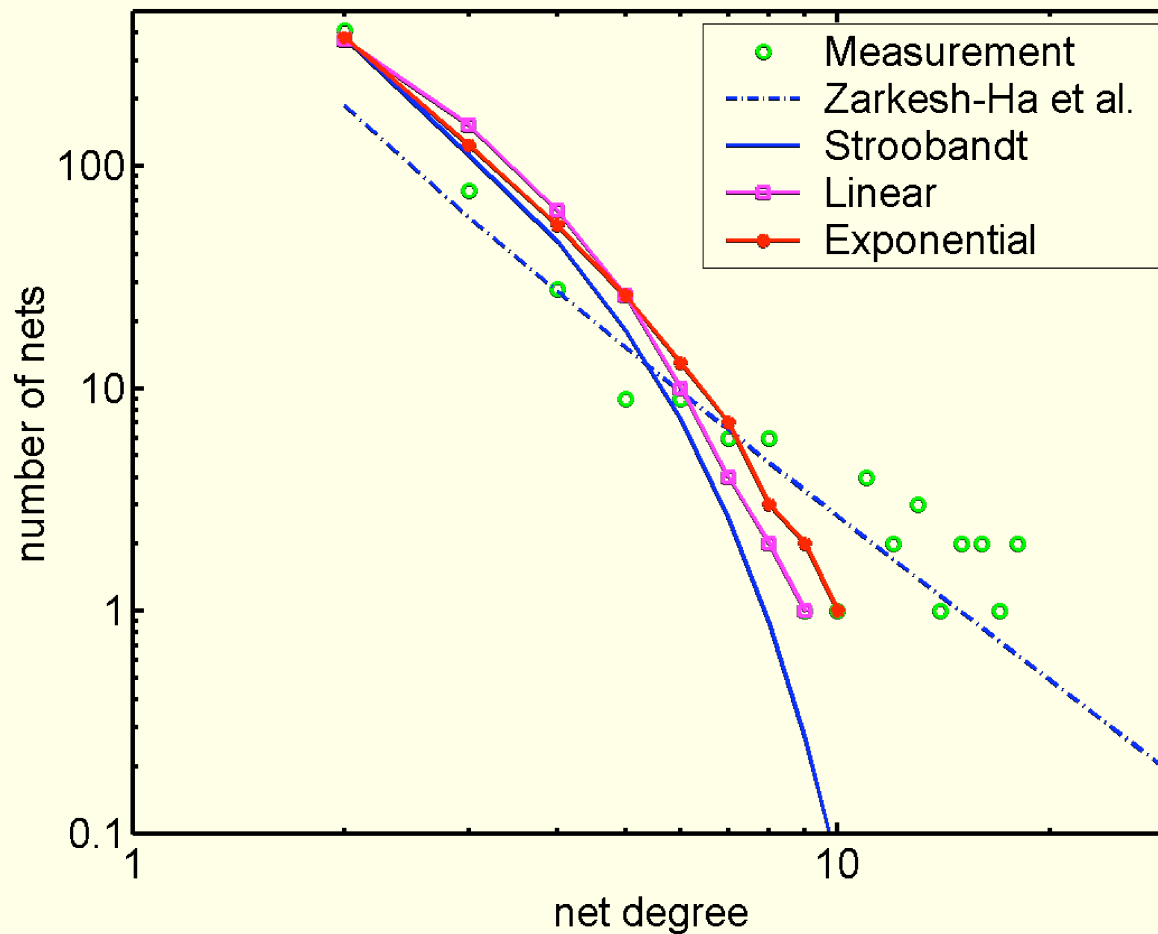
end.

A circuit of M blocks



Model 1 and Model 2

Net degree distribution of ISCAS89 benchmark s1196

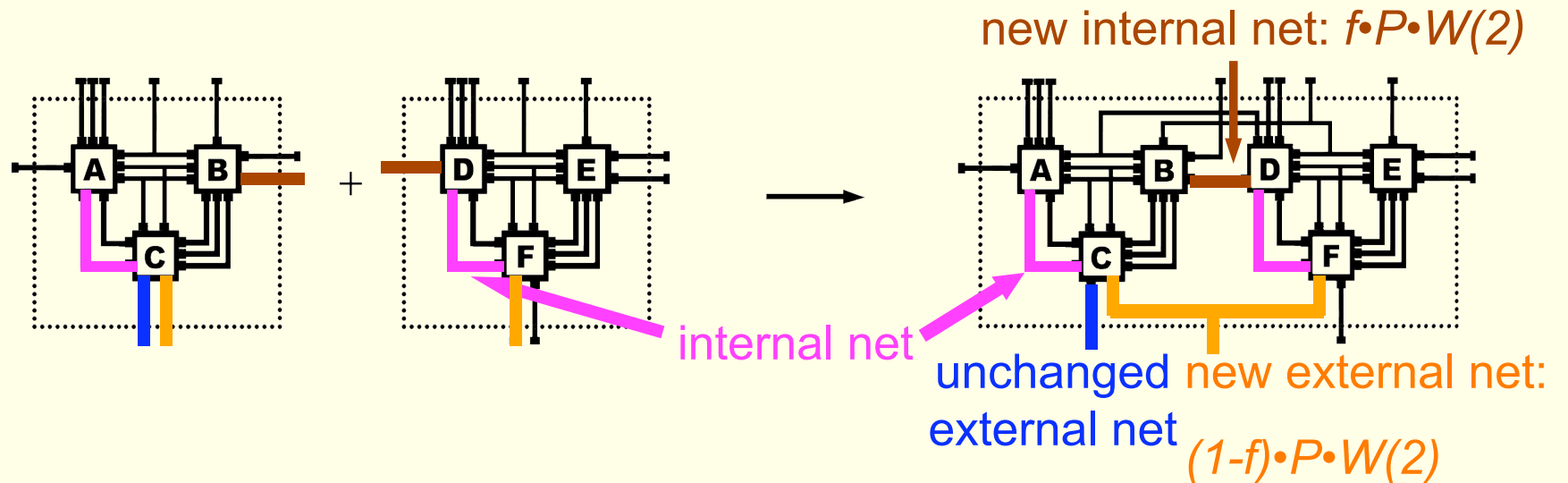
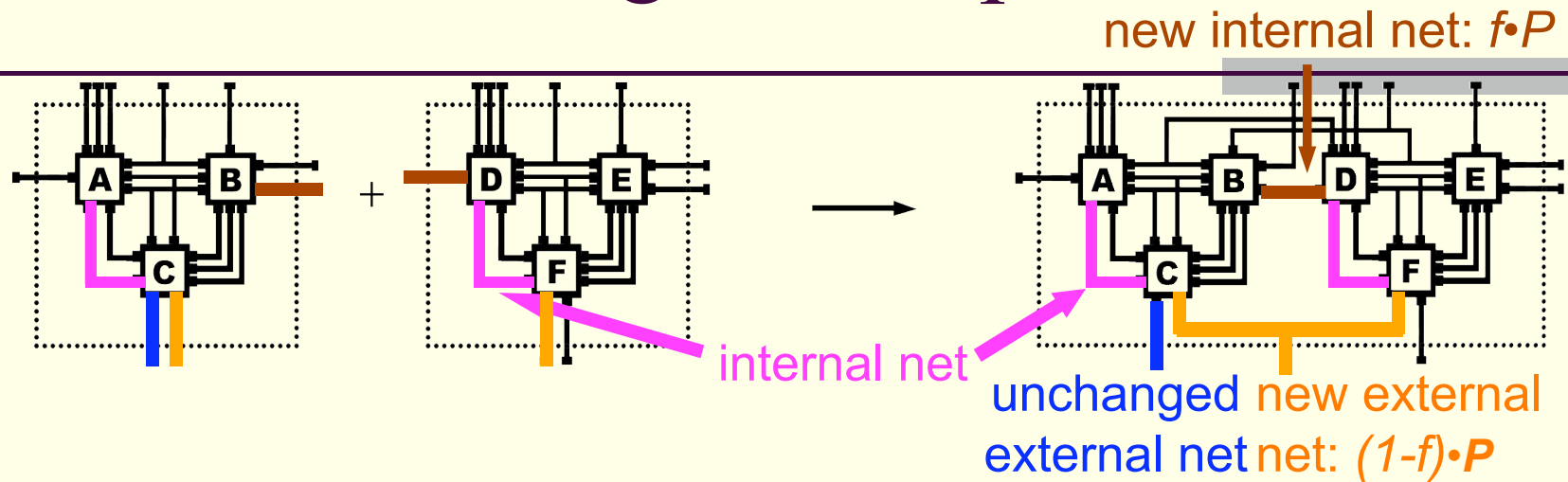


Model 3: Weighted Exponential

- Technology constraint and psychological constraint will result in the fact that nets with higher degrees are generated with higher probability
- We defined a vector $W(n)$ to associate the probability to the degree of newly generated nets

$$W(n) = |n - 3.5|^{0.7}$$

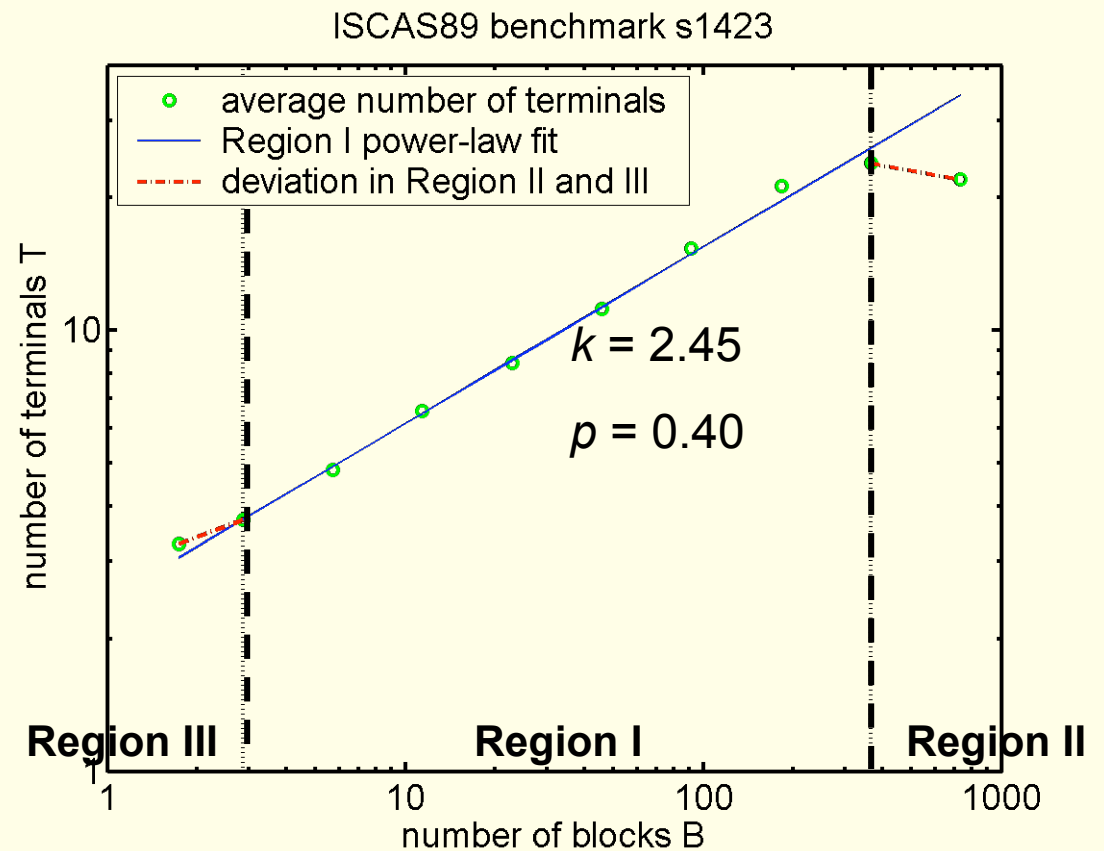
Model 3: Weighted Exponential



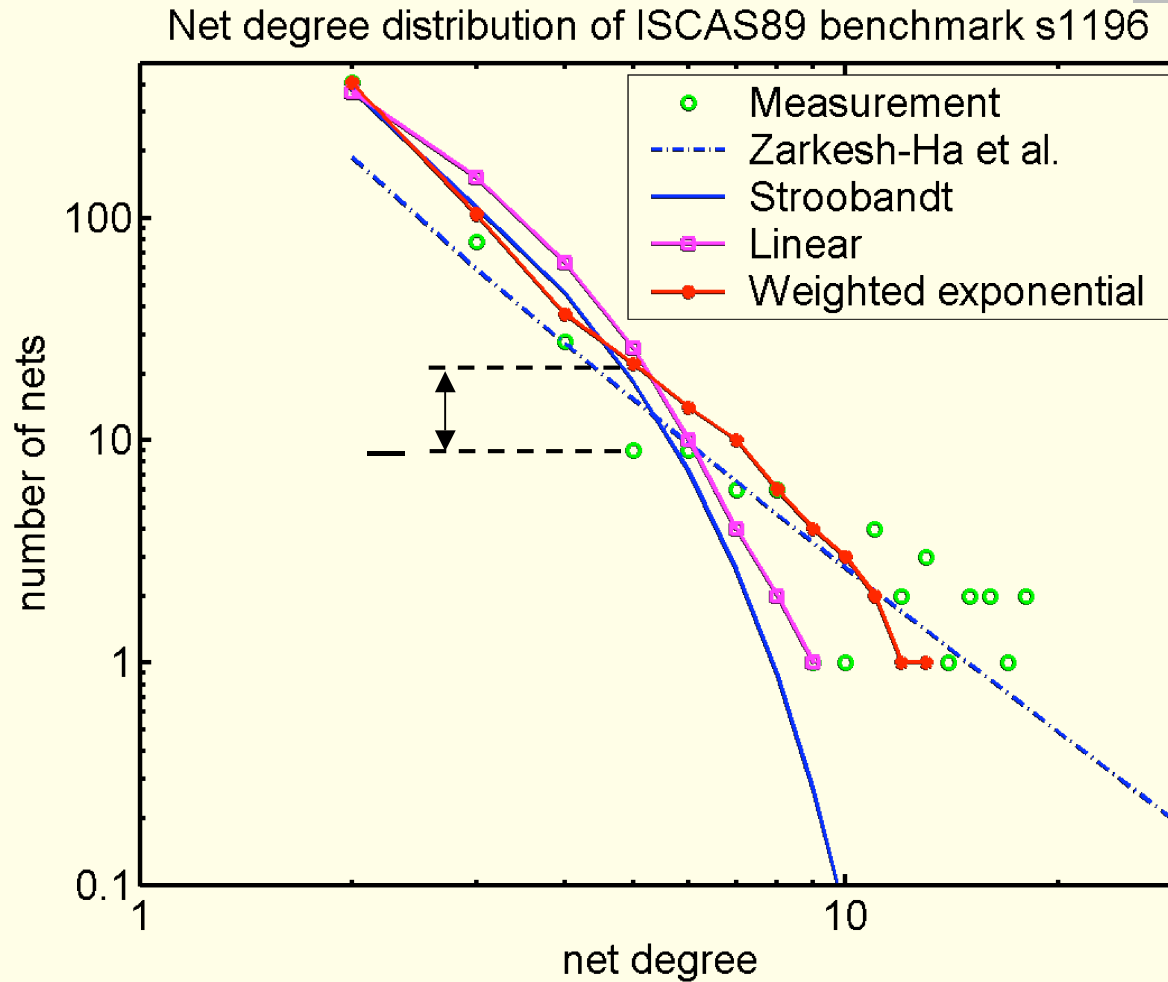
Experimental Results

- M : number of circuit blocks
 T : number of terminals
 N_{tot} : total number of nets
 - found for ISCAS89 benchmarks
- k and p : Rent's parameters
 - partitioning and Region I power-law fitting
- f : internal fraction factor

$$f = \frac{N_{tot} - T}{kM - N_{tot}}$$
- Net-degree distribution
 - counted by a Matlab program for ISCAS89 benchmarks



Experimental Results



The Least Squares Method: $\sum(\Delta^2)$

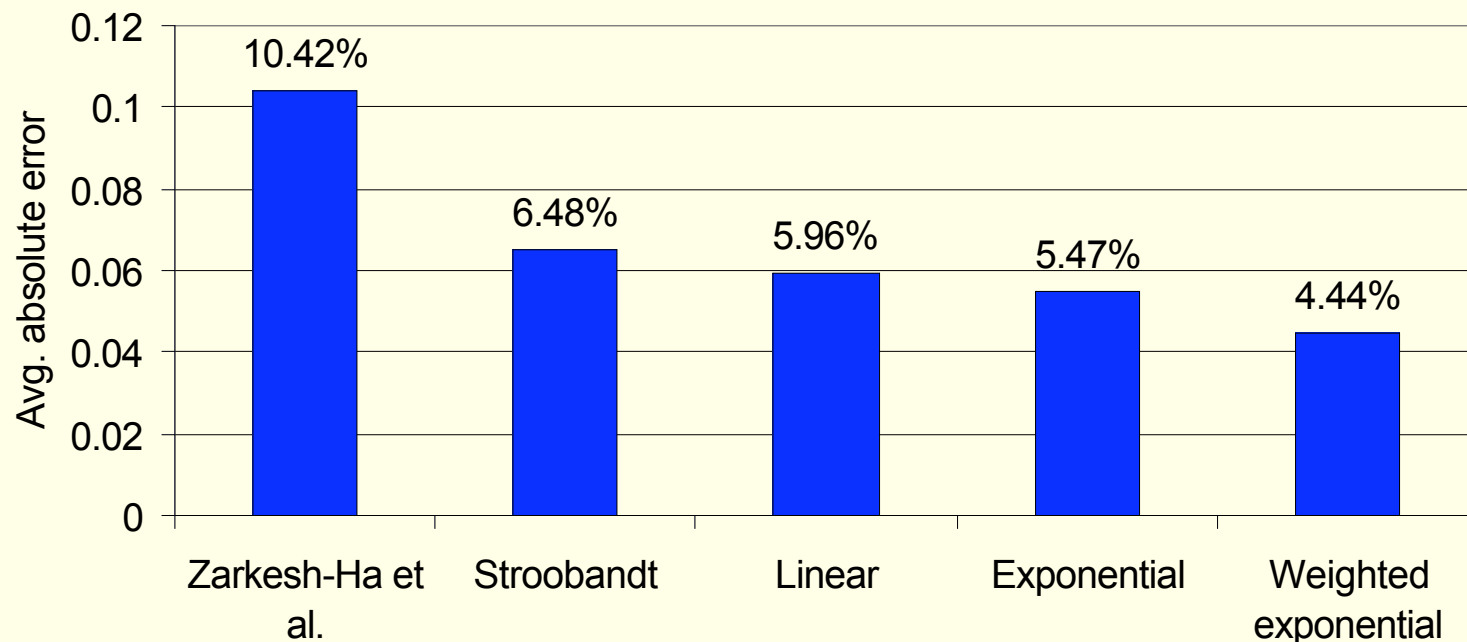
Name	Zarkesh-Ha et al.	Stroobandt	Linear	Exponential	Weighted exponential
s27	37	0	0	0	0
s208.1	1776	119	346	181	60
s298	1781	567	1191	605	302
s386	6195	3393	4401	3207	2126
s344	7126	525	940	640	264
s349	6961	551	994	659	280
s382	2107	467	1909	721	263
s444	2481	147	601	143	133
s526	3512	1998	5265	2586	1345
s526n	3930	2051	5162	2602	1318
s510	9754	1436	1112	842	1103
s420.1	5915	929	3461	1431	555
s713	46509	638	1202	710	162
s953	21030	289	1783	901	1214

The distribution with smallest $\sum(\Delta^2)$ is the best approximation

Average Net Degree

$$\text{error} = \frac{|\text{prediction-measurement}|}{\text{measurement}}$$

Avg. error on prediction of avg. net degree

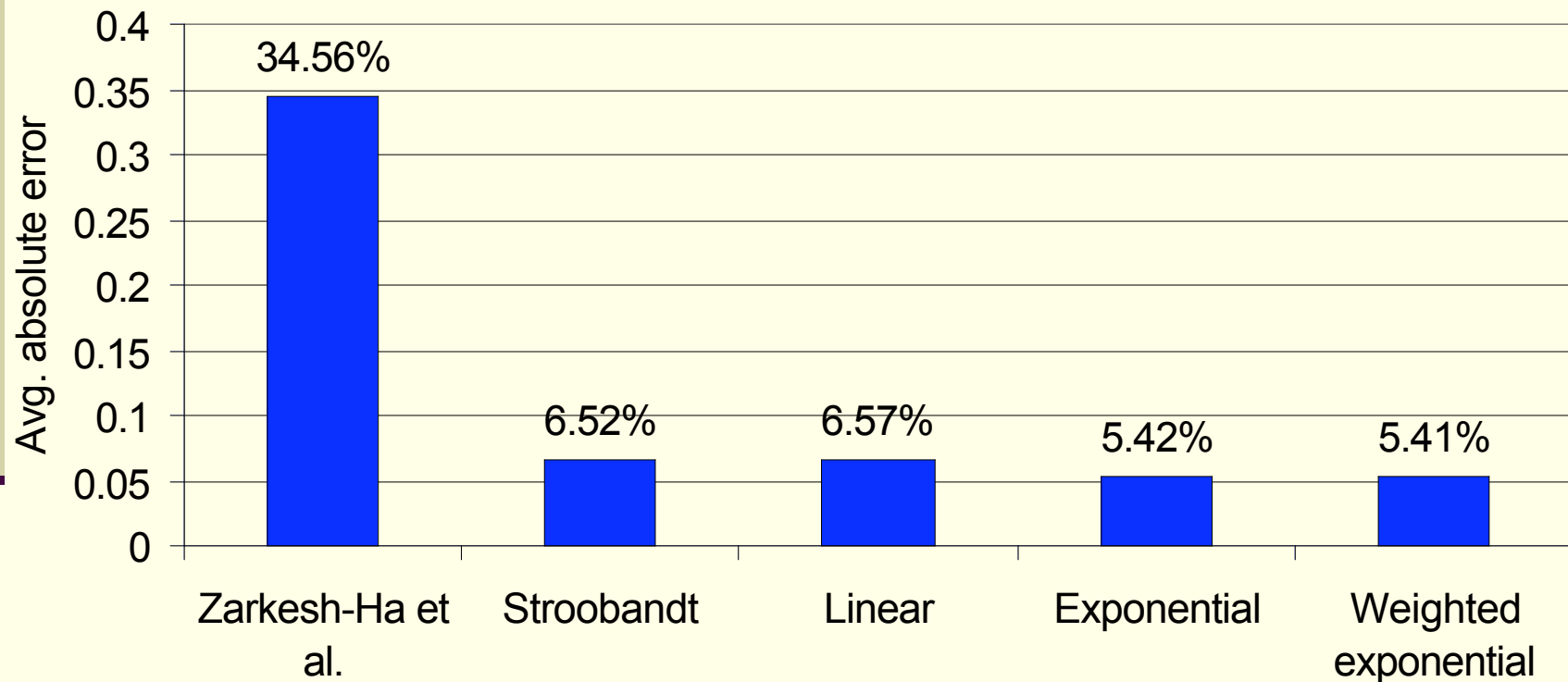


Average net degree and total number of nets are the most important parameters to represent interconnect complexity

Total Number of Nets

$$\text{error} = \frac{|\text{prediction} - \text{measurement}|}{\text{measurement}}$$

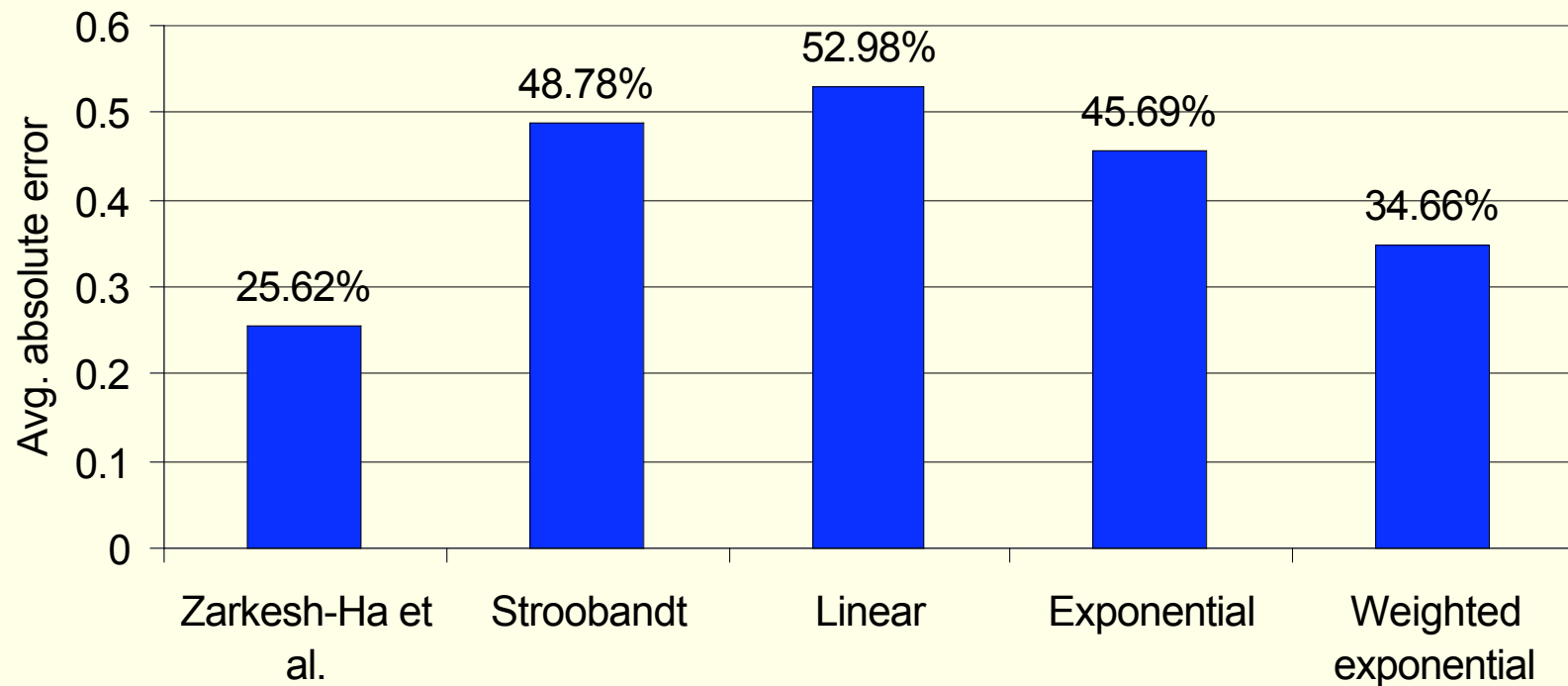
Avg. error on prediction of total number of nets



Maximum Fan-out

$$\text{error} = \frac{|\text{prediction-measurement}|}{\text{measurement}}$$

Avg. error on prediction of max. fan-out

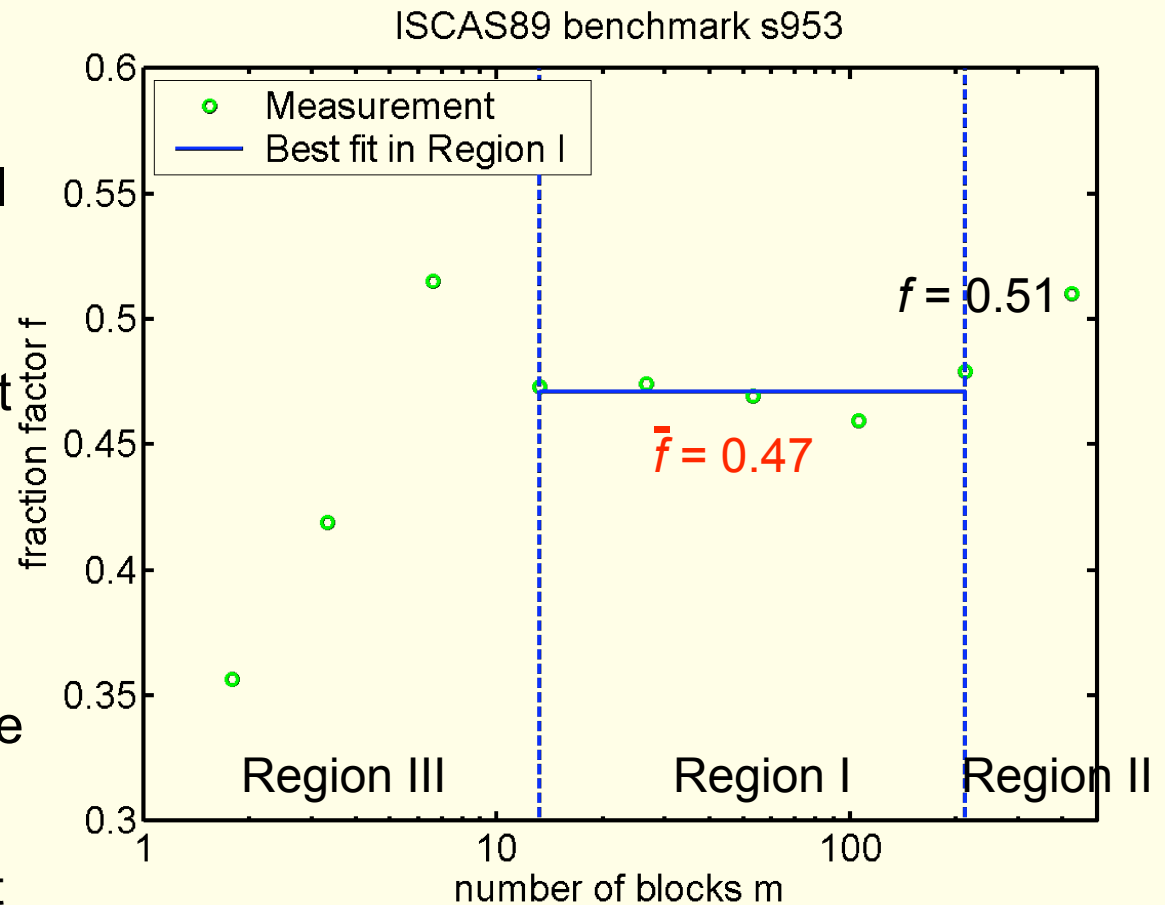


Maximum fan-out is important to predict the length of the longest path

Behavior of Internal Fraction Factor f

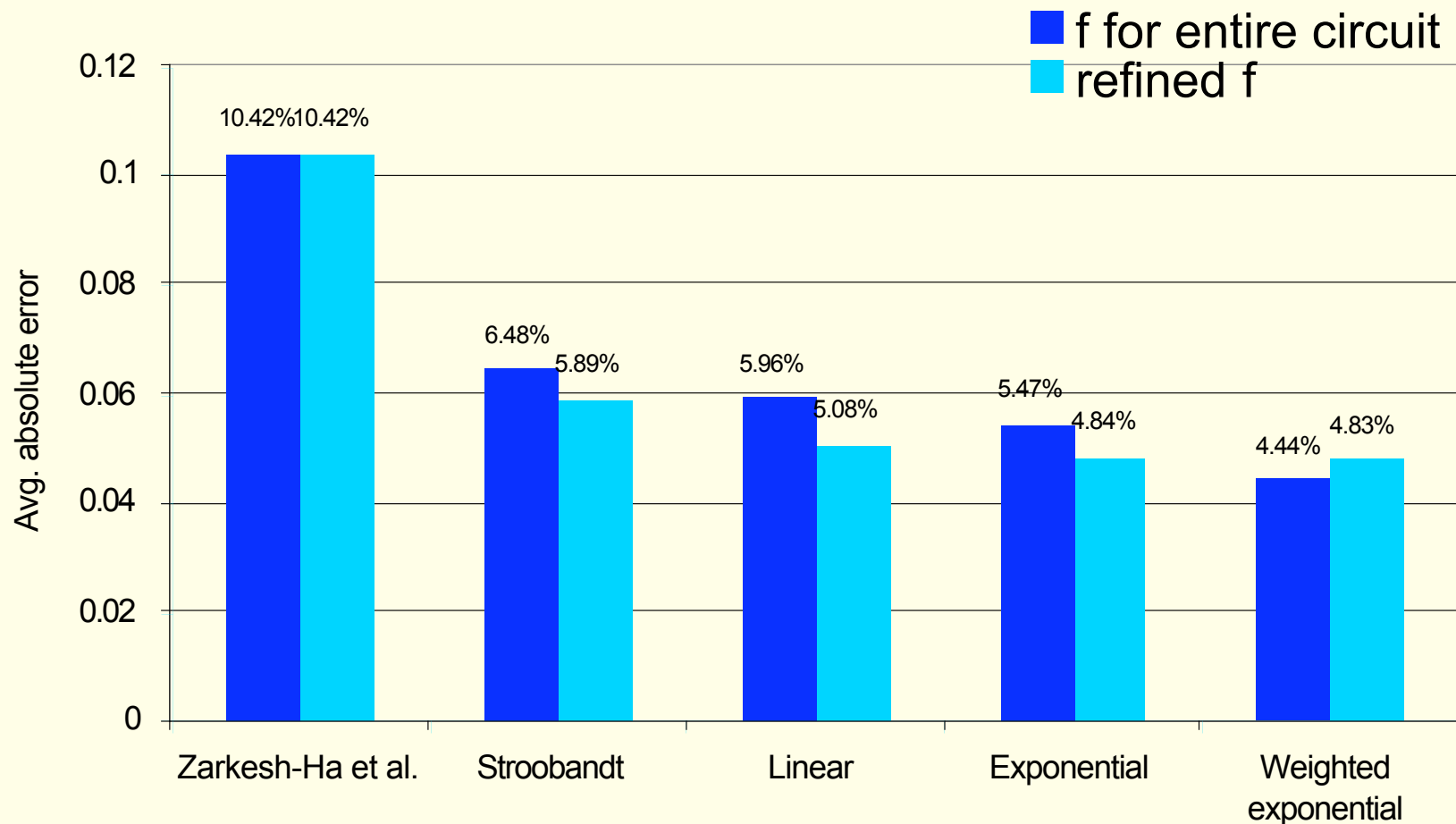
- Internal fraction factor f , similarly to Rent's rule, exhibits Region II and Region III
- We applied a best fitting procedure to get a refined value of f .
- With the refined value of f , our models and Stroobandt's model can provide even more accurate estimation

$$f = \frac{\text{new internal net}}{\text{new internal} + \text{new external}}$$



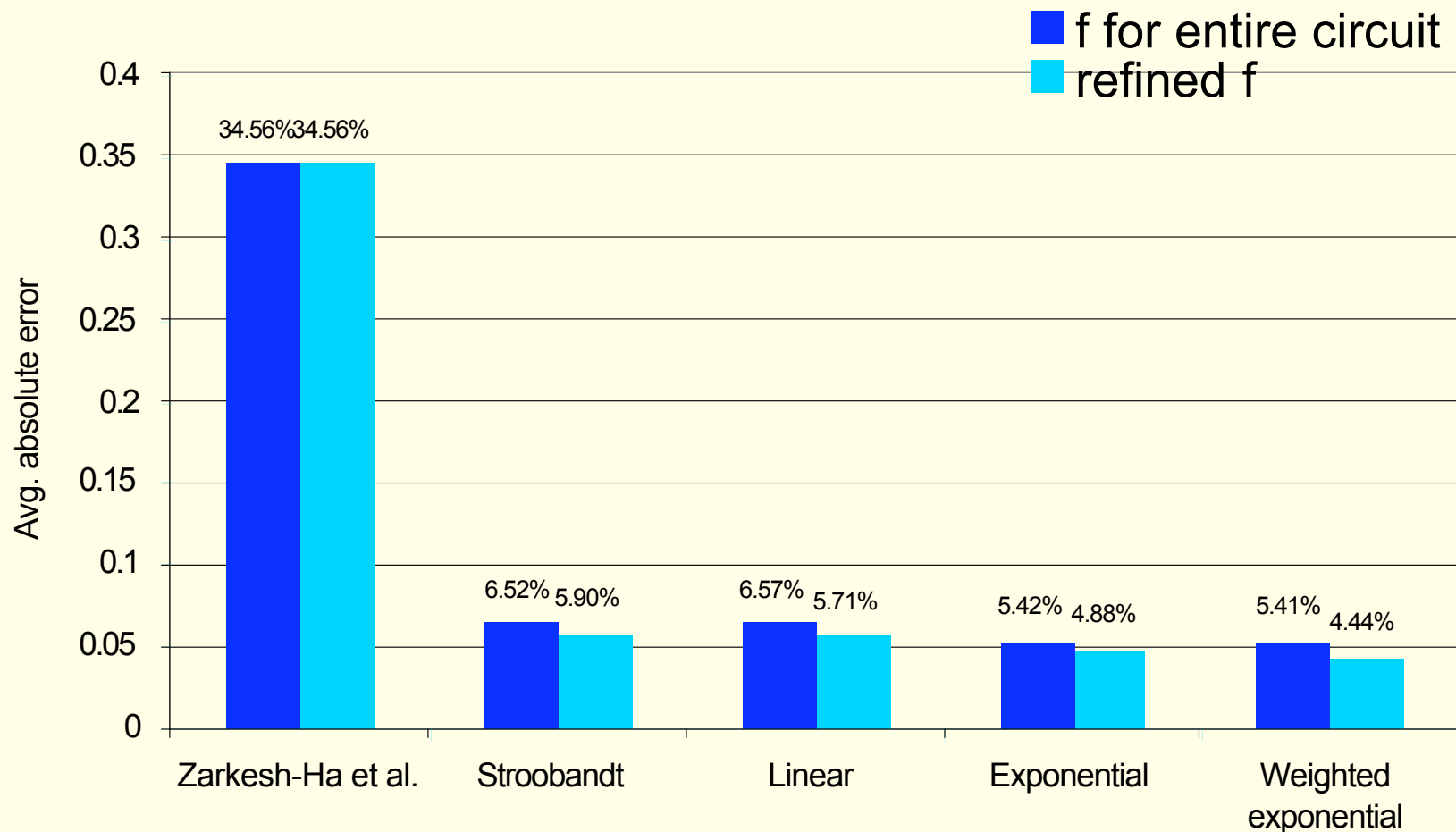
Comparison on Average Net Degree

Avg. error on prediction of average net degree



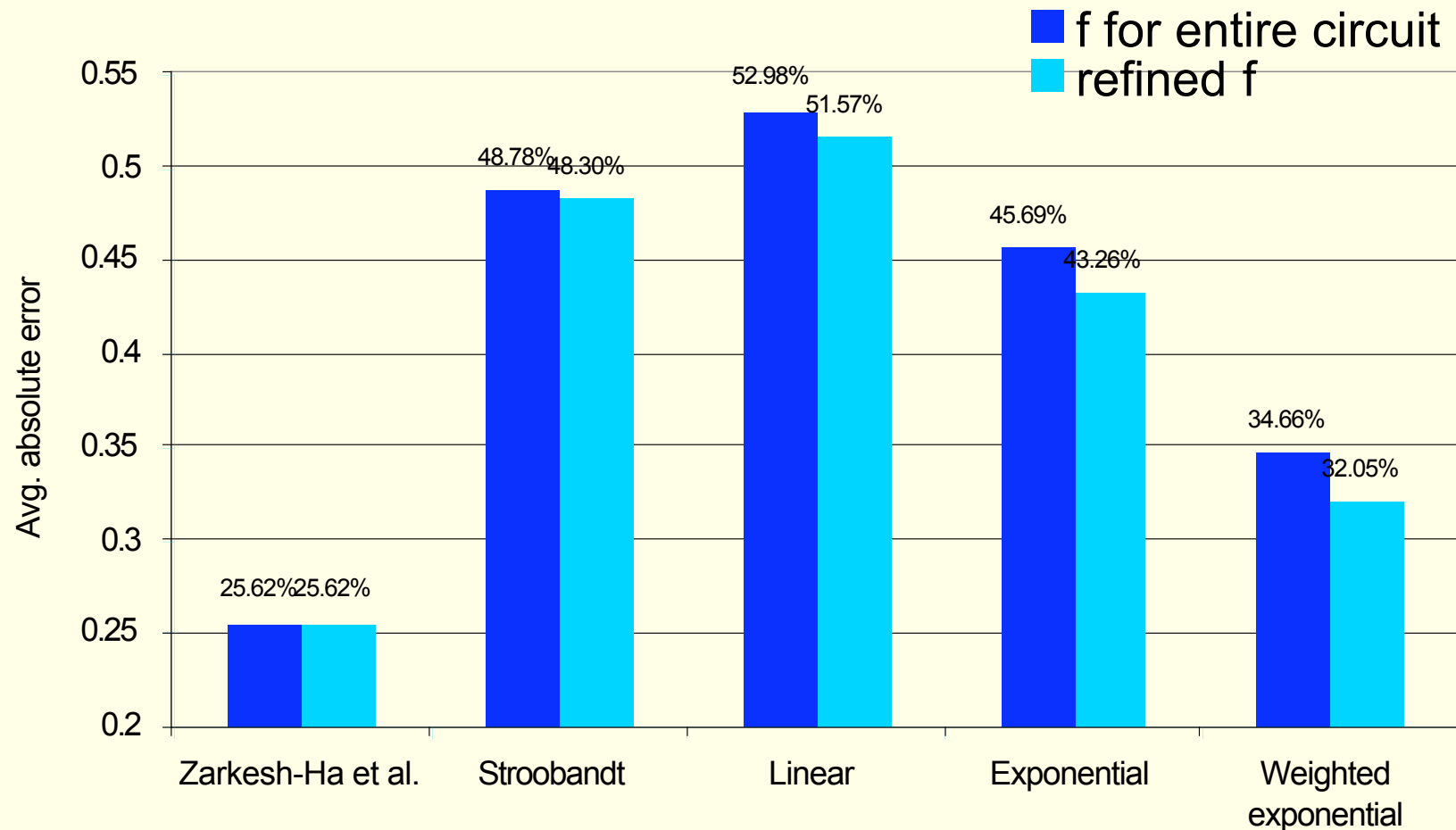
Comparison on Total Number of Nets

Avg. error on prediction of total number of nets



Comparison on Maximum Fan-out

Avg. error on prediction of max. fan-out



Conclusions

- We found an alternative way to derive net-degree distribution models by directly using normalized net-degree distribution
 - linear growth model
 - exponential growth model
 - weighted exponential model
- We accurately measured Rent's parameters k and p , internal fraction factor f and net-degree distribution of ISCAS89 benchmarks, which can be good references for other researchers

Conclusions

- For the first time, we observed that internal fraction factor f , similarly to Rent's rule, also exhibited Region II and Region III. With a refined value of f , our models and Stroobandt's model can provide even more accurate estimation of net-degree distribution
- Weighted exponential growing model is more accurate than any other currently available net-degree distribution model

	Avg. net degree	Total num. of nets	Max. fan-out
Zarkesh-Ha et al.	56.65%	87.15%	-25.10%
Stroobandt	18.00%	24.75%	28.95%

Accuracy enhancement of weighted exponential model

$$\text{accuracy enhancement} = \frac{\text{avg. error of Str.} - \text{avg. error of weighted}}{\text{avg. error of Stroobandt}}$$

Conclusions

- Weighted exponential model is a general theoretical model
 - applicable to various levels of circuit descriptions and various physical architectures
 - system level, circuit level, physical level
 - copper interconnect, optical interconnect
 - lots of possible applications
 - one example: a benchmark generator for floorplanning. Our tool, Bgen, generates more realistic benchmark circuits using weighted exponential model than when using other models